

<p><b><i>Notice of References Cited</i></b></p>	<p>Application/Control No. 09/524,358</p>	<p>Applicant(s)/Patent Under Reexamination OISHI ET AL.</p>	
	<p>Examiner ANDREW L. NALVEN</p>	<p>Art Unit 2434</p>	<p>Page 1 of 1</p>

## U.S. PATENT DOCUMENTS

* *		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
* *	A	US-4,078,152	03-1978	Tuckerman, III, Louis Bryant	380/37
* *	B	US-5,008,935	04-1991	Roberts, Thomas J.	380/29
* *	C	US-5,241,599	08-1993	Bellovin et al.	713/171
* *	D	US-5,594,793	01-1997	Bahout, Yvon	713/193
* *	E	US-5,765,197	06-1998	Combs, James Lee	711/164
* *	F	US-5,943,421	08-1999	Grabon, Robert J.	380/269
* *	G	US-6,202,152	03-2001	Yuenyongsgool et al.	713/189
* *	H	US-6,378,071	04-2002	Sasaki et al.	713/165
* *	I	US-6,385,727	05-2002	Cassagnol et al.	713/193
* *	J	US-5,237,460	08-1993	Miller et al.	360/8
* *	K	US-6,157,720	12-2000	Yoshiura et al.	380/44
* *	L	US-5,615,020	03-1997	Keith, Michael	382/246
* *	M	US-5,761,302	06-1998	Park, Tae Joon	380/201

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP0851627A1	09-1995	Japan	Hino et al	
	O					
	P					
	Q					
	R					
	S					
	T					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.